

Search Notes

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Examiner

Christopher L. Chin

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

1641

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	5/2/2005	CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR